Acta Crystallographica Section E

Structure Reports

Online

ISSN 1600-5368

N,N'-Ethylenebis(*p*-toluenesulfonamide)

Alison S. Gajadhar-Plummer, a Ishenkumba A. Kahwa and Joel T. Mague^{b*}

^aChemistry Department, University of the West Indies, Mona Campus, Kingston 7, Jamaica, and ^bDepartment of Chemistry, Tulane University, New Orleans, LA 70118, USA

Correspondence e-mail: joelt@tulane.edu

Key indicators

Single-crystal X-ray study $T=293~\mathrm{K}$ Mean $\sigma(\mathrm{C-C})=0.003~\mathrm{\mathring{A}}$ R factor = 0.036 wR factor = 0.110 Data-to-parameter ratio = 15.3

For details of how these key indicators were automatically derived from the article, see http://journals.iucr.org/e.

The title compound, $C_{16}H_{20}N_2O_4S_2$, crystallizes in a 'partially extended' conformation, with crystallographically imposed centrosymmetry and intermolecular $N-H\cdots O$ hydrogen bonding.

Received 7 December 2000 Accepted 14 December 2000 Online 22 December 2000

Comment

N,N'-Ethylenebis(p-toluenesulfonamide), (I), was prepared for use as a starting material in the synthesis of N-substituted alkylaminopolycarboxylate compounds, which were sought for development as potential biomedical diagnostics. The molecule crystallizes in a 'partially extended' conformation in which the tosyl group folds back towards the diaminoethane unit. The molecule possesses crystallographically imposed centrosymmetry and is associated in the crystal via intermolecular $N-H\cdots O$ hydrogen bonds.

Experimental

The title compound was prepared according to the procedure of Vogel (1989) and recrystallized from methanol. Analysis calculated for $C_{16}H_{20}N_2O_4S_2$: C 51.9, H 5.4, N, 7.6%; found: C 51.9, H 5.8; N, 7.5%.

Crystal data

 $\begin{array}{l} {\rm C_{16}H_{20}N_2O_4S_2} \\ {M_r} = 368.46 \\ {\rm Monoclinic,} \ P2_1/c \\ {a} = 5.8070 \ (12) \ \mathring{\rm A} \\ {b} = 8.0970 \ (16) \ \mathring{\rm A} \\ {c} = 18.513 \ (4) \ \mathring{\rm A} \\ {\beta} = 98.35 \ (3)^{\circ} \\ {V} = 861.2 \ (3) \ \mathring{\rm A}^3 \\ {Z} = 2 \\ {D_x} = 1.421 \ {\rm Mg \ m}^{-3} \end{array}$

Data collection

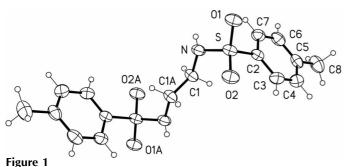
Enraf–Nonius CAD-4 diffract-ometer $\theta/2\theta$ scans Absorption correction: empirical $via\ \psi$ scans (North $et\ al.$, 1968) $T_{\min}=0.817,\ T_{\max}=0.829$ 3356 measured reflections 1682 independent reflections 1283 reflections with $I>2\sigma(I)$

 $D_m=1.4~{
m Mg~m}^{-3}$ D_m measured by flotation Mo $K\alpha$ radiation Cell parameters from 25 reflections $\theta=14.2-18.7^{\circ}$ $\mu=0.33~{
m mm}^{-1}$ $T=293~(2)~{
m K}$ Column, colourless $0.40\times0.36\times0.23~{
m mm}$

 $R_{\rm int} = 0.025$ $\theta_{\rm max} = 26.0^{\circ}$ $h = -7 \rightarrow 7$ $k = 0 \rightarrow 9$ $l = -22 \rightarrow 22$ 2 standard reflections frequency: 120 min intensity decay: 4.3%

DOI: 101107/S1600536800020298

© 2001 International Union of Crystallography Printed in Great Britain – all rights reserved



Perspective view of the title molecule. The pairs of atoms C1/C1A, O1/O1A etc are related by the crystallographic inversion centre.

Refinement

 $\begin{array}{lll} \text{Refinement on } F^2 & w = 1/[\sigma^2(F_o^2) + (0.0683P)^2 \\ R[F^2 > 2\sigma(F^2)] = 0.036 & + 0.1576P] \\ wR(F^2) = 0.110 & \text{where } P = (F_o^2 + 2F_c^2)/3 \\ S = 1.03 & (\Delta/\sigma)_{\text{max}} = 0.008 \\ 1682 \text{ reflections} & \Delta\rho_{\text{max}} = 0.35 \text{ e Å}^{-3} \\ 110 \text{ parameters} & \Delta\rho_{\text{min}} = -0.43 \text{ e Å}^{-3} \end{array}$

Table 1 Hydrogen-bonding geometry (Å, °).

$D-H\cdots A$	$D-\mathrm{H}$	$H \cdot \cdot \cdot A$	$D \cdot \cdot \cdot A$	$D-\mathrm{H}\cdot\cdot\cdot A$
N-H1N···O1i	0.86	2.34	2.971 (2)	131

Symmetry code: (i) 1 - x, 2 - y, -z.

H atoms were refined with fixed individual displacement parameters [$U(H) = 1.2~U_{\rm eq}(C),~U(H) = 1.3~U_{\rm eq}(C_{\rm methyl})$ or $U(H) = 1.2~U_{\rm eq}(N)$] using a riding model with N-H = 0.86, C-H(aromatic) = 0.93, C-H(methylene) = 0.97 or C-H(methyl) = 0.96 Å. The methyl group was allowed to rotate about its local threefold axis.

Data collection: *CAD-4 Software* (Enraf–Nonius, 1989); cell refinement: *CAD-4 Software*; data reduction: *XCAD4* (Harms & Wocadlo, 1987); program(s) used to solve structure: *SHELXS*97 (Sheldrick, 1990); program(s) used to refine structure: *SHELXL*97 (Sheldrick, 1997); molecular graphics: *SHELXTL* (Bruker, 1997); software used to prepare material for publication: *SHELXTL*.

We thank the Inter-American Development Bank-UWI development program (Project #29) for support and the UWI and Government of St Lucia for a Scholarship to ASGP. We also thank the Chemistry Department of Tulane University for support of the X-ray laboratory.

References

Bruker (1997). SHELXTL. Version 5.1. Bruker AXS Inc., Madison, Wisconsin, USA.

Enraf-Nonius (1989). CAD-4 Software. Enraf-Nonius, Delft, The Netherlands

Harms, K. & Wocadlo, S. (1987). XCAD4. University of Marburg, Germany. North, A. C. T., Phillips, D. C. & Mathews, F. S. (1968). Acta Cryst. A24, 351–359.

Sheldrick, G. M. (1990). Acta Cryst. A46, 467-473.

Sheldrick, G. M. (1997). SHELXL97. University of Göttingen, Germany.Vogel, A. (1989). Textbook of Practical Organic Chemistry, 5th ed., p. 1275.London: Longman.